MC3102F • MC3002F MC3102L • MC3002LP



This device consists of four 2-input NOR gates. Each gate may be used as an inverter, or two gates may be cross-coupled to form bistable circuits.



Positive Logic: $3 = \overline{1+2}$ Negative Logic: $3 = \overline{1 \cdot 2}$

Input Loading Factor = 1 Output Loading Factor = 10 Total Power Dissipation = 122 mW typ/pkg Propagation Delay Time = 6.0 ns typ

SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



 $C_T = 25 \text{ pF}$ = total parasitic capacitance, which includes probe, wifing, and load capacitances.

The coax delays from input to scope and output to scope must be matched. The scope must be terminated in 50-ohm impedance. The 950-ohm resistor and the scope termination impedance constitute a 20:1 attenuator probe. Coax shall be CT-070-50 or equivalent.

See General Information section for packaging.

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one gate. The other gates are tested in the same manner. Further, test procedures are shown for only one input of the gate under test. To complete testing, sequence through remaining inputs.



							TEST	CURRE	NT/VOLT/	TEST CURRENT/VOLTAGE VALUES				
	Tart		Am							>	Volts			
Ter	Temperature	10	ы	5	-	۲ ^н	×H^	Υ,	V _R	V _{RH}	Vmax	Vcc	VccL	V _{CCH}
	(-55°C	20	-2.0	•		1.1	2.0 0.4	0.4	2.4	4.0		5.0	4.5	5.5
MC3102	+25°C	20	-2.0	1.0	1.0 -10	1.1	1.8	0.4	2.4	4.0	0.7.0	5.0	4.5	5.5
	(+125°C	20	-2.0	•	,	0.8	1.8	0.4	2.4	4.0		5.0	4.5	5.5
	0°C	20	-2.0	•		1.1	2.0	0.4	2.5	4.0		5.0	4.75	5.25
MC3002	{ +25°C	20	-2.0		1.0 -10	1.1 1.8		0.4	2.5	4.0	7.0	5.0	4.75	5.25
	(+75°C	20	-2.0	1	•	0.9	0.9 1.8	0.4	2.5	4.0		5.0	4.75	5.25
nits					TECT	CIRPS	V/ IN:	OLTAG	E APPILED	TECT CLIPDENT / VOLTAGE ADDITED TO DING LISTED BELOW	ICTED BEL	. MO		

Prim Model of the prime Model of the prime </th <th></th> <th>20</th> <th>-2.0</th> <th></th> <th></th> <th>0.9</th> <th>1.8</th> <th>0.4</th> <th>2.5</th> <th>4.0</th> <th></th> <th>0.0</th> <th>4.15</th> <th>07.70</th> <th>-</th>																	20	-2.0			0.9	1.8	0.4	2.5	4.0		0.0	4.15	07.70	-
Nick 5° $+0^{\circ}$ $+-5^{\circ}$ $+0^{\circ}$ N_{ee}			Pin		W	3102	Test Lin	nits			¥	C3002	Test Lin	nits						TEST	CURRE	NT / V	OLTAG	APPLIED	TO PINS LIS	TED BEL	: MO			
	-		Under	1	55°C	+2	5°C	+	25°C	-)°C	+	25°C	Ŧ	15°C				L			T	F							T
$ \ \ \ \ \ \ \ \ \ \ \ \ \ $	Characteristic	Symbol	Test	Min	Max							-				_	_	но	5	-	V _n	× H	>"	× ×		Vmax		V _{cct}	VccH	Gnd
	Input Forward Current	IF	1	•	-2.0		-2.0		-2.0	-	-2.0	-	-2.0		-2.0		L	_	·				-		2		1	·	14	*4
Votage BV _{II} 1 5.5 5.5 5.5 5.5 5.5 5.5 15 15 16 - 10 - 10 - 1.5 15 5 - 5 5 - 5 5 - 15 5 - 5	Leakage Current	IR	-		50		50	·	50		50		50	•	50	μAdc	1	•						-					14	2,7*
	Breakdown Voltage	BVin	-			5.5	1	1.		1.0	·	5.5	1		·	Vdc		•	-	1							۰.		14	2,7*
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Clamp Voltage	VD	1	1	ι.		-1.5			1			-1.5	-		Vdc	-		1.	-								14	1	*1
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		HOA	3	2.4	•	2.4		2.4	-	2.5	-	2.5	-	2.5	-	Vdc		8		•	-							14		2,7*
	Short-Circuit Current	Isc	e	-40	-100	-40	-100		-100		-100		-100			1					1		1					•	14	1, 2, 3, 7*
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Power Requirements (Total Device) Maximum Power Supply Current	Imax	14	I.	1		38		1		'		38			mAdc			· •						2 - A.	14		•	1	1, 2, 4, 5, 7, 9, 10, 12, 13
	Power Supply Drain		14	1	45		45	!	45		45	1	45		45	mAdc		•		•	1				1, 2, 4, 5, 9, 10, 12, 13		'		14	2
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$		Iddl	14	•	28		28	•	28		28		28	•	28	mAdc	-	1	1.			1.	1.					•	14	1, 2, 4, 5, 7, 9, 10, 12, 13
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Switching Parameters				н с ц ⁷				-								Pulse	Pulse												
total transformed and the second seco	Turn-On Delay	t _{pd-}	1,3		.e.,		10	•	•	•	'	•	10	1	•	su	-	8		•	1		•	,	1	•	14	•	•	2,7*
	Turn-Off Delay	t _{pd+}	1, 3	÷,			10				•	•	10	•	•	us	1	e			•						14	•		2,7*

MC3102, MC3002 (continued)

*Since this is an inverting gate, power drain is minimized by grounding the inputs to gates not under test.